Search Notes



Apı	olic	atio	n/C	ont	rol	No),

Applicant(s)/Patent under Reexamination

ARONSON ET AL.

10/706,651

Examiner

Art Unit 2874

James D. Stein

SEARCHED					
Class	Subclass	Date	Examiner		
385	88,92,93,9 4	7/13/2005	JDS		
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	

(INCLUDING SEARCH	STRATEGY)
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See attached updated EAST search history	7/13/2005	JDS
IEEE and INSPEC: optical, housing, lens, facets parallel, TOSA, ROSA	7/13/2005	JDS